

Application/Control No.	Applicant(s)/Patent under Reexamination
10/672,151	JACOBS ET AL.
Examiner	Art Unit
 Binh X. Tran	1765

SEARCHED					
Class	Subclass	Date	Examiner		
438	710	7/18/2005	31		
438	712	7/18/2005	奶		
438	714	7/18/2005	Bt		
438	723	7/18/2005	Bi		
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INT	INTERFERENCE SEARCHED					
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SEARCH NOT (INCLUDING SEARCH)
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Updated search using USPAT, US-PGPUB, JPO, EPO, DERWENT	7/18/2005	B
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